



IBM POUGHKEEPSIE

Diagnostic Engineering Publication

1410/7010

December 1, 1963

Subject: Diagnostic Program WT01B 1415 I/O Printer Test
Sequence Number 551
Replaces WT01A

When WT01 is in card form card # 001 is a System Control Card. It does not have any control information punched in it when it is released.

Refer to "1410/7010 Introduction", Volume 1.00 for instructions on how it must be punched.

This is a modified and improved version of WT01A. The modifications include:

- A. Changes necessary to be compatible with the current diagnostic format.
- B. Removal of the test routine called "WMS AND BLANKS IN M & L MODES."
- C. Alteration and expansion of the test routine called "WM ALIGNMENT AND WM PERIOD TESTS."
- D. Inclusion of a new test routine to check on band width (detenting difference) and alignment.
- E. Changing the timing section to type out the time it took to type each line instead of each pair of lines. The timing routine (now) covers 7010 as well as 1410 systems.
- F. Changing the method in which the optional "SELECTED CHARACTER ROUTINE" (build your own test pattern routine) operates.

Enclosures: 26 Pages

Card Deck for CARD ONLY SYSTEMS (as punched by UP51)

8	Cards - Card Loader (1-7) and 1 Core Clear
62	Cards No. 001-062 Data Cards
1	Card Execute Card

Distribution: X 1410
X 7010
Other

WT01

1415 CONSOLE I/O PRINTER TEST

(1410/7010)

December 1, 1963

CONTENTS OF WT01 WRITE-UP AND LISTING

5.00.00.0	Test Description	Page 3
5.00.01.0	Loading Procedures	Page 6
5.00.02.0	Operating Procedures	Page 6
5.00.03.0	Operating Hints, Comments	Page 7
5.00.04.0	Program Stops (Halts) and Restarts	Page 8
5.00.05.0	Typeouts	Page 8
5.00.06.0	Flow Charts	Page N/A
5.00.07.0	Appendices	Page 9
5.00.08.0	Listings	Page 13
	Summary	Page 25

5.00.00.0 TEST DESCRIPTION

00.1 MODIFICATIONS

This is a modified and improved version of WT01A. The modifications include:

- A. Changes necessary to be compatible with the current diagnostic format. (Standard TADs at location 01000 and a Standard System Control Card to provide necessary system information and eliminate unnecessary operator intervention.)
- B. Removal of the test routine called "WMS AND BLANKS IN M & L MODES." This test routine contributed little to the overall effectiveness of the test.
- C. Alteration and expansion of the test routine called "WM ALIGNMENT AND WM PERIOD TESTS." See description, Section 5.00.00.2, for further information.
- D. Inclusion of a new test routine to check on band width (detenting difference) and alignment.
- E. Changing the timing section to type out the time it took to type each line instead of each pair of lines. The timing routine (now) covers 7010 as well as 1410 systems.
- F. Changing the method in which the optional "SELECTED CHARACTER ROUTINE" (build your own test pattern routine) operates. See OPERATING PROCEDURES, Section 5.00.02.2.

00.2 DESCRIPTION

WT01 is a functional test of the Program Printout Operations of the 1415 Console I/O Printer on the 1410 or 7010 Data Processing System. Test routines are directed toward checking Character Printout, Space, Word-Mark Control, and Carriage Return and Indexing Operations. The Input Operation is tested through the use of the Console Inquiry function.

5.00.00.0 TEST DESCRIPTION (continued)

Test patterns are designed to test specific operations or phases of operations. Before each pattern is typed, the title of the test pattern selection character is typed (see Section 5.00.02.2 for use of test pattern selection character).

The test patterns, their titles and test objectives are explained in the order in which they are run. Each test line of characters is typed twice for (visual) comparison.

COLLATING SEQUENCE A

Type all characters in the COLLATING SEQUENCE for convenient visual checking.

ROCK B

Test the tilt mechanism by typing the characters located one after the other in vertical columns on the print head.

ROLL C

Test the rotate mechanism by selecting characters one after the other in horizontal bands around the print head.

TWIST D

Test the combined rotate and tilt mechanism by causing a maximum rotation and tilt between characters.

WM ALIGNMENT AND WM PERIOD TESTS E

Exercise thoroughly spacing and backspacing mechanisms by typing word marks over every other character and then over every character. The word-mark period latch is given specific attention here.

BANDWIDTH & ALIGNMENT TEST F

The characters typed are chosen specifically to test band width (detenting difference), alignment and the action of the wear compensator. The characters, \$!QNLJ, are chosen because of their rotate selections. If a band width exists, it will be greatest among these characters. They are also used in a final check during alignment (fine tuning). The "J" is used extensively to cause the wear compensator to take up slack in the rotate and select system.

5.00.00.0 TEST DESCRIPTION (continued)

All test pattern selection characters should line up in position 42 on the margin scale as a test of the spacing operation.¹

Carriage return is always tested in two ways, by margin lever stop and again by a group mark word mark at the end of the write field. All fixed test patterns are 83 characters long. Because of the printout identification character (R normally) and the space that follows it, the first test pattern character is typed in position three and the last in position eighty-five if the tabs are set correctly. A carriage return and indexing operation is therefore initiated by both the B channel group mark word mark and an end of line condition. This produces a double space between each pair of lines of every test pattern. Look for this to occur.

00.3 EQUIPMENT

Any model 1410 or 7010 Data Processing System. The 1415 Console I/O Printer is the only I/O device tested. It is assumed to be on E channel only.

The Processing Overlap Feature is not necessary but is done in overlap mode if it is available.

00.4 CARD DECK

A complete card deck of WT01 consists of the following:

7 cards	Loader
1 card	Execute (Core Clear)
program cards ²	Program WT01
1 card	Execute (branch to 02000)

Note: Card No. 001 is a System Control Card. It does not have any control information punched in it when it is released. See "1410/7010 Introduction," Volume 1.00, for instructions on how to punch it.

00.5 EC LEVEL OF MACHINE

Not applicable.

- ¹ Be sure to follow instructions on setting up margin lever stops as explained in OPERATING PROCEDURES, Section 5.00.02.1.
- ² See Release sheet for exact number of cards.

5.00.01.0 LOADING PROCEDURES

Use Standard Diagnostic Loading Procedure. Refer to "1410/7010 Introduction," Volume 1.00, for further information.

5.00.02.0 OPERATING PROCEDURES

- 02.1 Always set the right and left hand margin lever stops to their maximum right and left hand positions (0 and 85, respectively). The test patterns and the character position count both depend on this. A group of four-digit numbers separated by slashes occurs in one line of this test for counting purposes. The units position of each number corresponds to the position of the character with respect to the left-hand margin. The printout identification character R is counted as number one.

WT01 begins immediately on completion of loading and no manual intervention is required.

- 02.2 Test operation can be altered at any time by using the "Program Alter Routine." An Inquiry Request is acknowledged upon completion of any line of type. TADs are loaded as blanks and the locations are only tested for 1. TAD5, a Special TAD, is an exception and its use is described fully.

Standard TADs

<u>TADs</u>	<u>Address</u>	<u>Not 1</u>	<u>1</u>
TAD0	01000	Do Not	Bypass Typeouts
TAD1	01001	Do Not	Loop on Routine
TAD2	01002	Do Not	Halt on Error
TAD3	01003	Do Not	Repeat Test

Special TADs

TAD4	01004	Do Not	Typeout time to type 1 line
TAD5	01005	Do Not	Select Test Pattern by letter

TAD 0 is used only to bypass an error message typeout.

Setting TAD 4 to a 1 causes a typeout of the time it took to type the line preceding it to be given. Use only on systems with the Processing Overlap Feature.

WT01
Page 7
12/31/64

5.00.02.0 OPERATING PROCEDURES (continued)

Use TAD 5 to select a particular test pattern by name (actually by letter). If it remains a blank, all test routines are run in order. Entering the test pattern selection character (A, B, C, ..., F) causes the test to go directly to the pattern selected. The test patterns and the letters that relate to them are covered in the description, Section 5.00.00.1. Entering an X causes the test to go to the "SELECTED CHARACTER ROUTINE." After entering an M or an L in response to "ENTER MODE- M OR L," the request "ENTER DATA FIELD" is made. At this time a full line of characters with or without word marks may be entered. If the number of characters entered is less than a full line (83), the portion entered is expanded to produce a full line typeout. To have less than a full line typed out, enter a group mark word mark after the last character to be typed. The line of characters is typed twice unless TAD1 is set to loop on routine. Entering a Z in TAD5 takes the program to the end of job message and into the next test.

5.00.03.0 OPERATING HINTS, COMMENTS

03.1 On systems equipped with overlap all test routines are typed in overlap mode. This makes it convenient to give typeouts of the length of time it takes to type a given line on request. If it is necessary to operate in unoverlap mode, reload the test, press STOP while "WT01" is being typed out, alter location 01263 to a blank, RESET and START. The test is started over from the beginning including the necessary initialization.

Should it ever be necessary to time (approximately) a carriage return operation instead of a normal line print operation, the following is offered. Use the SELECTED CHARACTER ROUTINE to type a simple line, preferably blanks (b's) in Load Mode or zeros (0's). Set TAD 1 to loop on routine (location 01001 to a 1) and TAD4 to a 1 for timing. With the right hand margin selector on 85 (end of line), take several lines of outputs. Now set the margin selector to 84. This causes a carriage return and the last character of the line to be typed in column 1. The time difference between the two lines is carriage return time (approximately).

1. Timing can only be used on systems with the Processing Overlap Feature.

5.00.03.0 OPERATING HINTS, COMMENTS

- 03.2 The time for one pass of WT01 including all test routines, titles, etc., but no timing typeouts or Inquiry Requests is approximately 4 minutes.
- 03.3 The SELECTED CHARACTER ROUTINE can be used to investigate the Output Error Routine by entering a group mark word mark for the data field. This causes an underscored zero (0) followed by underscored blanks (b) to be typed. All characters are typed in column 1. Once this operation is initiated, it is not under program control and STOP or RESET must be used to terminate it.

5.00.04.0 PROGRAM STOPS, RESTARTS

There are no Normal Stops in WT01 and only one Error Stop. It is under TAD control and occurs only if TAD 2 is set to 1. The STOP follows an error typeout indicating a data check error. Push START to continue the test.

RESET and START causes the test to begin again at 02000, repeating the typeout of the test identification and performing all the initialization.

5.00.05.0 TYPEOUTS

- 05.1 The only typeout that has not been explained in preceding sections or may need clarification is:

*** DATA CHECK IN LAST LINE TYPED ***

This message indicates that a parity check error (Data Check) occurred during the typing of the test line above it. The character or characters involved should be underscored.

5.00.02.0 OPERATING PROCEDURES (continued)

Use TAD 5 to select a particular test pattern by name (actually by letter). If it remains a blank, all test routines are run in order. Entering the test pattern selection character (A, B, C, ... F) causes the test to go directly to the pattern selected. The test patterns and the letters that relate to them are covered in the description, Section 5.00.00.1. Entering an X causes the test to go to the "SELECTED CHARACTER ROUTINE." After entering an M or an L in response to "ENTER MODE- M OR L," the request "ENTER DATA FIELD" is made. At this time a full line of characters with or without word marks may be entered. If the number of characters entered is less than a full line (83), the portion entered is expanded to produce a full line typeout. To have less than a full line typed out, enter a group mark word mark after the last character to be typed. The line of characters is typed twice unless TAD1 is set to loop on routine. Entering a Z in TAD5 takes the program to the end of job message and into the next test.

5.00.03.0 OPERATING HINTS, COMMENTS

- 03.1 On systems equipped with overlap all test routines are typed in overlap mode. This makes it convenient to give typeouts of the length of time it takes to type a given line on request. If for some reason it is necessary to operate in unoverlap mode once the test is in progress, alter location 01263 to a blank (location denotes overlap in System Control Card), RESET and START. The test is started over from the beginning including the necessary initialization.

Should it ever be necessary to time (approximately) a carriage return operation instead of a normal line print operation, the following is offered. Use the SELECTED CHARACTER ROUTINE to type a simple line, preferably blanks (b's) in Load Mode or zeros (0's). Set TAD 1 to loop on routine (location 01001 to a 1) and TAD4 to a 1 for timing. With the right hand margin selector on 85 (end of line), take several lines of outputs. Now set the margin selector to 84. This causes a carriage return and the last character of the line to be typed in column 1. The time difference between the two lines is carriage return time (approximately).

1. Timing can only be used on systems with the Processing Overlap Feature.

5.00.03.0 OPERATING HINTS, COMMENTS

- 03.2 The time for one pass of WT01 including all test routines, titles, etc., but no timing timeouts or Inquiry Requests is approximately 4 minutes.
- 03.3 The SELECTED CHARACTER ROUTINE can be used to investigate the Output Error Routine by entering a group mark word mark for the data field. This causes an underscored zero (0) followed by underscored blanks (b) to be typed. All characters are typed in column 1. Once this operation is initiated, it is not under program control and STOP or RESET must be used to terminate it.

5.00.04.0 PROGRAM STOPS, RESTARTS

There are no Normal Stops in WT01 and only one Error Stop. It is under TAD control and occurs only if TAD 2 is set to 1. The STOP follows an error timeout indicating a data check error. Push START to continue the test.

RESET and START causes the test to begin again at 02000, repeating the timeout of the test identification and performing all the initialization.

5.00.05.0 TYPEOUTS

- 05.1 The only typeout that has not been explained in preceding sections or may need clarification is:

*** DATA CHECK IN LAST LINE TYPED ***

This message indicates that a parity check error (Data Check) occurred during the typing of the test line above it. The character or characters involved should be underscored.

APPENDIX

1415 CONSOLE PRINTER

TRANSLATOR, OUTPUT

<u>BCD Bits</u>	<u>Magnet Picked</u>
$\overline{2}$	R1
$\overline{8} \cdot 4$	R2
$\overline{8} + 4$	R2A
$8 \cdot \overline{1} + \overline{8} \cdot 1$	R5
\overline{A}	T1
\overline{B}	T2
\overline{C}	CK
$8 \cdot 4 \cdot 2 \cdot 1 + 8 \cdot 4$	UC
All others	LC
V (Word Mark)	UC. CK
_ (Underscore)	UC. CK. T1. T2

TRANSLATOR, INPUT

<u>Contacts Transferred</u>	<u>BCD Bit</u>
$R5 \cdot \overline{R2A} \cdot LC + \overline{R5} \cdot R2A + \overline{R5} \cdot UC$	1
$R1 \cdot \overline{R2A} + LC \cdot R1$	2
$R2 \cdot \overline{R2A}$	4
$R2A \cdot LC + \overline{R2A} \cdot UC$	8
T1	A
T2	B
CK + Space	C
Word Mark	WM

Contracts transfer when corresponding magnet is NOT picked, except R5 which transfers when magnet is picked.
Keyboard to contact coding is same as magnets picked.

1415 CONSOLE PRINTER

Character	BCD Code	Magnets Picked									
b (Blank)	C		R1	R2	R2A		T1	T2	UC	*	
. (Period)		B A 8 2 1							C		LC
)	C	B A 8 4	R1		R2A R5						UC
[B A 8 4 1	R1		R2A				C		UC
<		B A 8 4 2			R2A R5				C		UC
≠ (Group Mark)	C	B A 8 4 2 1			R2A						UC
& (Ampersand) +	C	B A	R1	R2	R2A						UC *
\$	C	B 8 2 1					T1				LC
*		B 8 4	R1		R2A R5		T1		C		UC
]	C	B 8 4 1	R1		R2A		T1				UC
;	C	B 8 4 2			R2A R5		T1				UC
Δ		B 8 4 2 1			R2A		T1		C		UC
-		B	R1	R2	R2A		T1		C		UC *
/	C	A 1	R1	R2	R2A R5			T2			LC *
, (Comma)	C	A 8 2 1						T2			LC
% {) (A 8 4	R1		R2A R5			T2	C		UC
~ (Wd Separator)	C	A 8 4 1	R1		R2A			T2			UC
\	C	A 8 4 2			R2A R5			T2			UC
## Segment Mark		A 8 4 2 1			R2A			T2	C		UC
Ⓢ Substitute		A	R1	R2	R2A			T2	C		UC *
# Blank =		8 2 1					T1	T2	C		LC
@ ,	C	8 4	R1		R2A R5		T1	T2			UC
:		8 4 1	R1		R2A		T1	T2	C		UC
>		8 4 2			R2A R5		T1	T2	C		UC
⌈ (Tape Mark)	C	8 4 2 1			R2A		T1	T2			UC
?	C	B A 8 2			R5						LC
A		B A 1	R1	R2	R2A R5				C		LC
B		B A 2		R2	R2A				C		LC
C	C	B A 2 1		R2	R2A R5						LC
D		B A 4	R1		R2A				C		LC
E	C	B A 4 1	R1		R2A R5						LC
F	C	B A 4 2			R2A						LC
G		B A 4 2 1			R2A R5				C		LC
H		B A 8	R1		R5				C		LC
I	C	B A 8 1	R1								LC
I		B 8 2			R5	T1			C		LC
J	C	B 1	R1	R2	R2A R5	T1					LC
K	C	B 2		R2	R2A	T1					LC
L		B 2 1		R2	R2A R5	T1			C		LC
M	C	B 4	R1		R2A	T1					LC
N		B 4 1	R1		R2A R5	T1			C		LC
O		B 4 2			R2A	T1			C		LC
P	C	B 4 2 1			R2A R5	T1					LC

* From keyboard R5 selected instead of R1, R2, R2A.

1415 Console Printer (continued)

Character	BCD Code				Magnets Picked								
Q	C	B	8		R1		R5	T1				LC	
R		B	8	1	R1			T1	C			LC	
≠ (Record Mark)		A	8	2			R5		T2	C		LC	
S	C	A		2 1		R2	R2A	R5		T2		LC	
T		A		2 1		R2	R2A	R5		T2	C	LC	
U	C	A	4		R1		R2A			T2		LC	
V		A	4	1	R1		R2A	R5		T2	C	LC	
W		A	4	2			R2A			T2	C	LC	
X	C	A	4	2 1			R2A	R5		T2		LC	
Y	C	A	8		R1			R5		T2		LC	
Z		A	8	1	R1					T2	C	LC	
0	C		8	2				R5	T1	T2		LC	
1				1	R1	R2	R2A	R5	T1	T2	C	LC	
2				2		R2	R2A			T1	T2	C	LC
3	C			2 1		R2	R2A	R5	T1	T2		LC	
4			4		R1		R2A			T1	T2	C	LC
5	C		4	1	R1		R2A	R5	T1	T2		LC	
6	C		4	2			R2A			T1	T2		LC
7			4	2 1			R2A	R5	T1	T2	C	LC	
8			8		R1			R5	T1	T2	C	LC	
9	C		8	1	R1					T1	T2		LC
v (Word Mark)											C	UC	
(Underscore)										T1	T2	C	UC

*** END OF JOB ***

I/O PRINTER TEST

PGLIN	LABEL	OPCCD	OPERAND	CT	ADDR	INSTRUCTION
1002	LOADER	EQU	400			
1003						
1004	*	*****	STANDARD TADS	*****		
1005		ORG	1000		01000	
1006	*		NOT 1			
1007	TAD0	DC	2 2	DO NOT	BYPASS TYPE OUTS	1 01000
1008	TAD1		2 2	DO NOT	LOOP ON ROUTINE	1 01001
1009	TAD2		2 2	DO NOT	HALT ON ERRORS	1 01002
1010	TAD3		2 2	DO NOT	REPEAT PROGRAM	1 01003
1011						
1012						
1013						
1014						
1015	*	*****	SPECIAL TADS	*****		
1016						
1017	TAD4	DC	2 2	DO NOT	TYPEOUT TIME TO TYPE 1 LINE	1 01004
1018					USE ONLY IF SYSTEM HAS OVERLAP	
1019	TAD5		2 2	DO NOT	SELECT TEST PATTERN BY LETTER	1 01005
1020						
1021						
1022						
1023						
1024						
1025						
1026						
1027						
1028						
1029						
1030						
1031	GMWM	DCW	2 2			1 01006

TEST SET UP IN THE NOT 1 CONDITION
AND WILL ONLY CHECK FOR A 1

* THE FOLLOWING MAY BE USED IN
TADS TO SELECT TEST PATTERNS
A TEST A COLLATING SEQUENCE
B TEST B ROCKING EXERCISE
C TEST C ROLLING EXERCISE
D TEST D TWISTING EXERCISE
E TEST E WORDMARK ALIGNMENT
F TEST F BANDWIDTH-ALIGNMENT
X TEST X SELECTED CHARACTERS
Z THEEND EOJ MESSAGE C B 400

PGLIN	LABEL	OPCODE	OPERAND	CT	ADDRES	INSTRUCTION
1033	*		*PROGRAM ALTER AND CONTROL ROUTINE			
1034	CONTRL	SBR	CTLXIT ^S	7	01007	G 01081 B
1035	ENTER	RCP	ADDRES ^S	10	01014	M 01049 R
1036		BNT1	CTLXIT ^T	7	01024	R 01076 B
1037		BEX1	ENTER ^M	7	01031	R 01014 M
1038		BAL	ADDRES	7	01038	R 01045 M
1039		RCPW	00000 ^S	10	01045	L 010000 R
1040	ADDRES	BEX1	ADDRES ^M	7	01055	R 01045 M
1041		BAL	*01	7	01062	R 01069 M
1042						
1043						
1044		B	TSTSEL	7	01069	J 01083
1045						
1046	CTLXIT	B	00000	7	01076	J 00000
1047	*					
1048	*					
1049	*					
1050	TSTSEL	BCE	TESTA,TAD5,A	12	01083	B 02007 01005 A
1051		BCE	TESTB,TAD5,B	12	01095	B 02160 01005 B
1052		BCE	TESTC,TAD5,C	12	01107	B 02251 01005 C
1053		BCE	TESTD,TAD5,D	12	01119	B 02342 01005 D
1054		BCE	TESTE,TAD5,E	12	01131	B 02433 01005 E
1055		BCE	TESTF,TAD5,F	12	01143	B 02555 01005 F
1056		BCE	TESTX,TAD5,X	12	01155	B 02653 01005 X
1057		BCE	THEEND,TAD5,Z	12	01167	B 02993 01005 Z
1058		B	CTLXIT	7	01179	J 01076
1059	H		DEFINE PRECEDING BRANCH LENGTH	1	01186	.

COLLATING SEQUENCE

ROCK PATTERN

ROLL PATTERN

TWIST PATTERN

WM ALIGNMENT & WM PERIOD TESTS

BANDWIDTH AND ALIGNMENT ROUTINE

SELECTED CHARACTER ROUTINE

EOJ MESSAGE & B 400 - NEXT TEST

RETURN TO ALTER ROUTINE

DEFINE PRECEDING BRANCH LENGTH

I/O PRINTER TEST

WTOI PAGE 15

CT ADDR INSTRUCTION

PGLIN LABEL OPCCD OPERAND

1061		ORG	1230	CONTROL INFORMATION	01230
1062		DC	a		15 01244
1063		DC	255100a	SEQ# 551 SK SYS1 ONLY	5 01249
1064	TESTID	DCW	2NT01a	*TEST IDENTIFICATION	4 01253
1065	LEVEL	DC	2B2a.G		1 01254
1066					
1067		ORG	1256	*SYSTEM CONTROL CARD	01256
1068	SYS1	DC	a a	INDICATE SYSTEM TYPE	1 01256
1069				0 1410 STD	
1070				1 1410 ACC	
1071				X 7010	
1072			a	NOT INTERROGATED	6 01262
1073			a a	1-SYSTEM HAS OVERLAP	1 01263
1074			a	a NOT INTERROGATED	15 01278
1075			a	*a	10 01288
1076		ORG	1289		01289
1077					

UTILITY TYPING AND SPACING ROUTINE

1080	TYPEIT	SBR	TYPE88	STORE ADDRESS OF MESSAGE	7 01289 G 01304 B
1081	TYPE	WCP	00000	TYPE MESSAGE	10 01296 M 210 00000 M
1082		SBR	TYPEXT&5	STORE ADDRESS FOR RETURN	7 01306 G 01383 B
1083		BCB1	TYPE		7 01313 R 01296 2
1084		BAL	*&1	CONTINUE	7 01320 R 01327 M
1085		CW	SPACEX&1		6 01327 01358
1086	SPACE	SBR	SPACEX&6	EXIT WHEN SPACING	7 01333 G 01363 B
1087		WCP	ABLANK	CNE BLANK LOCATION	10 01340 M 210 01385 M
1088		BAL	*-16		7 01350 R 01340 M
1089	SPACEX	NCPWM			1 01357 N
1090		B	00000	EXIT WHEN SPACING	7 01358 J 00000
1091		SW	SPACEX&1		6 01365 01358
1092		BNQ	CONTRL	TO CONTROL ROUTINE	7 01371 J 01007 Q
1093	TYPEXT	B	00000	EXIT WHEN TYPING SUBTITLES, ETC	7 01378 J 00000
1094					
1095	ABLANK	DCW	a a.G	JUST FOR A SPACE	1 01385

PGLIN	LABEL	OPCODE	OPERAND	INITIALIZATION- DONE ON FIRST PASS ONLY	CT	ADDRS	INSTRUCTION
1097	*						
1098							
1099	SETUP	CS	99	CLEAR OUT TOP 100 ADDRESSES	6	01387	/ 00099
1100		MRCWG	B2000,1	SET UP RESET RESTART BRANCH AT 1	12	01393	D 01612 00001 L
1101		SW	95,25	SET WMS IN INDEX REGISTERS	11	01405	, 00095 00025
1102		MLWB	95,90	MOVE THEM ALL THE WAY THROUGH	12	01416	D 00095 00090 M
1103		ZA	OTIME,TIME	U SEC/PASS IN TIMING LOOP,1410	11	01428	M 01703 03587
1104		BCE	CK40LP,SYSL,0	SYSTEM IS STD 1410	12	01439	B 01485 01256 0
1105		ZA	ITIME,TIME	U SEC/PASS 1410 ACC	11	01451	M 01707 03587
1106		BCE	CK40LP,SYSL,1	SYSTEM IS 1410 ACC	12	01462	B 01485 01256 1
1107		ZA	XTIME,TIME	U SEC/PASS 7010	11	01474	M 01711 03587
1108	CK40LP	BCE	*E19,SYSL,7,	CHECK FOR OVERLAP	12	01485	B 01515 01263
1109		SW	OVRLAP,1	SET UP FOR OVERLAP	6	01497	, 03209
1110		MLCS	000,TYPE,TP,1	TYPE IN OVERLAP MODE	12	01503	D 04436 03199 3
1111		SW	PATRX,84	SET ADDRESS	6	01515	, 04436
1112		SAR	ENDOFX	IN INDEX REGISTER	7	01521	G 00049 A
1113		SW	TWGP,40	SETTING WORDMARK IN PATTERN	6	01528	, 04056
1114		SW	SPBSP1,SPBSP1,82	SET WMS IN TEST PATTERN	11	01534	, 04100 04182
1115		SW	SPBSP2,SPBSP2,82		11	01545	, 04184 04266
1116		MLWB	SPBSP1,82,SPBSP1,80	MOVE WMS OVER EVERY OTHER ONE	12	01556	D 04182 04180 M
1117		MLWB	SPBSP2,82,SPBSP2,81		12	01568	D 04266 04265 M
1118		MLCS	000,ENTERX,9	SET UP READ CONSOLE PRINTER	12	01580	D 04437 02797 3
1119		B	TYPEIT		7	01592	J 01289
1120		DCW	0WT01B,0,G		5	01603	
1121		B	TESTA	BEGIN TEST PATTERN SEQUENCE	7	01605	J 02007
1122							
1123	B2000	DCW	0J02000 0,G	RESET RESTART	7	01612	
1124		ORG	*EX00			01700	
1125	OTIME	DCW	00167	U SEC/PASS IN TIMING LOOP 1410	4	01703	
1126	ITIME		00133	U SEC/PASS IN TIMING LOOP 1410I	4	01707	
1127	XTIME		00047	U SEC/PASS IN TIMING LOOP 7010	4	01711	

I/O PRINTER TEST

W101
CT ADDR INSTRUCTION

PGLIN	LABEL	OPCODE	OPERAND	CT	ADDR	INSTRUCTION
1129		ORG	2000		02000	
1130	START	B	SETUP	7	02000	J 01387
1131						
1132						
1133	TESTA	B	SPACE	7	02007	J 01333
1134		B	TYPEIT	7	02014	J 01289
1135		DCW	ACOLLATING SEQUENCE	40	02060	
1136						
1137	TYPEA	B	WCP	7	02062	J 03100
1138		DCW	CSGP1	5	02073	03596
1139		B	WCP	7	02074	J 03100
1140		DCW	CSGP1	5	02085	03596
1141						
1142		B	SPACE	7	02086	J 01333
1143		B	WCP	7	02093	J 03100
1144		DCW	CSGP2	5	02104	03680
1145		B	WCP	7	02105	J 03100
1146		DCW	CSGP2	5	02116	03680
1147						
1148		B	SPACE	7	02117	J 01333
1149		B	WCP	7	02124	J 03100
1150		DCW	CSGP3	5	02135	03764
1151		B	WCP	7	02136	J 03100
1152		DCW	CSGP3	5	02147	03764
1153						
1154		BCE	TYPEA,TA01.1	12	02148	B 02062 01001 1

REPEAT PATTERN A

PGLIN	LABEL	OPCOD	OPERAND	CT	ADDRS	INSTRUCTION
1156	TESTB	B	SPACE	7	02160	J 01333
1157		B	TYPEIT	7	02167	J 01289
1158		DCW	ARCCK	40	02213	
1159						
1160	TYPEB	B	WCPW	7	02215	J 03115
1161		DCW	ROKGP	5	02226	03848
1162		B	WCPW	7	02227	J 03115
1163		DCW	ROKGP	5	02238	03848
1164						
1165		BCE	TYPEB,TAD1,1	12	02239	B 02215 01001 1
1166	*					
1167	*					
1168	*					
1169	TESTC	B	SPACE	7	02251	J 01333
1170		B	TYPEIT	7	02258	J 01289
1171		DCW	AROLL	40	02304	
1172						
1173	TYPEC	B	WCPW	7	02306	J 03115
1174		DCW	ROLGP	5	02317	03932
1175		B	WCPW	7	02318	J 03115
1176		DCW	ROLGP	5	02329	03932
1177						
1178		BCE	TYPEC,TAD1,1	12	02330	B 02306 01001 1
1179	*					
1180	*					
1181	*					
1182	TESTD	B	SPACE	7	02342	J 01333
1183		B	TYPEIT	7	02349	J 01289
1184		DCW	ATWIST	40	02395	
1185						
1186	TYPED	B	WCPW	7	02397	J 03115
1187		DCW	TWIGP	5	02408	04016
1188		B	WCPW	7	02409	J 03115
1189		DCW	TWIGP	5	02420	04016
1190						
1191		BCE	TYPED,TAD1,1	12	02421	B 02397 01001 1

I/O PRINTER TEST

WT01 INSTRUCTION

CT ADDR

OPCODE OPERAND

LABEL

PGLIN

TESTE

SPACE

TESTF

TYPEF

TYPEIT

COMMON UTILITY TYPING ROUTINE

TYPEIT

TYPEF

DCW

3WM ALIGNMENT AND WM PERIOD TESTS

DCW

DCW

WCPW

TYPE TEST PATTERN IN LOAD MODE

WCPW

WCPW

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

WCPW

TYPE TEST PATTERN IN LOAD MODE

WCPW

WCPW

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

TYPE TEST PATTERN IN LOAD MODE

SPACE

SPACE

WCPW

SPACE AND BACKSPACE GROUP 2

WCPW

WCPW

SPBSP2

TYPE TEST PATTERN IN LOAD MODE

SPBSP2

SPBSP2

SPACE

SPACE AND BACKSPACE GROUP 2

SPACE

SPACE

BCE

REPEAT PATTERN E

BCE

BCE

SPACE

SPACE

SPACE

SPACE

TYPEIT

TYPEIT

TYPEIT

TYPEIT

DCW

BANDWIDTH & ALIGNMENT TEST

DCW

DCW

WCP

BANDWIDTH AND ALIGNMENT GROUP

WCP

WCP

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

SPACE AND BACKSPACE GROUP 1

SPACE

SPACE

WCPW

TYPE TEST PATTERN IN LOAD MODE

WCPW

WCPW

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

SPACE AND BACKSPACE GROUP 1

SPACE

SPACE

BCE

REPEAT PATTERN F

BCE

BCE

SPACE

SPACE

SPACE

SPACE

TYPEIT

TYPEIT

TYPEIT

TYPEIT

DCW

BANDWIDTH & ALIGNMENT TEST

DCW

DCW

WCP

BANDWIDTH AND ALIGNMENT GROUP

WCP

WCP

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

SPACE AND BACKSPACE GROUP 1

SPACE

SPACE

WCPW

TYPE TEST PATTERN IN LOAD MODE

WCPW

WCPW

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

SPACE AND BACKSPACE GROUP 1

SPACE

SPACE

BCE

REPEAT PATTERN F

BCE

BCE

SPACE

SPACE

SPACE

SPACE

TYPEIT

TYPEIT

TYPEIT

TYPEIT

DCW

BANDWIDTH & ALIGNMENT TEST

DCW

DCW

WCP

BANDWIDTH AND ALIGNMENT GROUP

WCP

WCP

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

SPACE AND BACKSPACE GROUP 1

SPACE

SPACE

WCPW

TYPE TEST PATTERN IN LOAD MODE

WCPW

WCPW

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

SPACE AND BACKSPACE GROUP 1

SPACE

SPACE

BCE

REPEAT PATTERN F

BCE

BCE

SPACE

SPACE

SPACE

SPACE

TYPEIT

TYPEIT

TYPEIT

TYPEIT

DCW

BANDWIDTH & ALIGNMENT TEST

DCW

DCW

WCP

BANDWIDTH AND ALIGNMENT GROUP

WCP

WCP

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

SPACE AND BACKSPACE GROUP 1

SPACE

SPACE

WCPW

TYPE TEST PATTERN IN LOAD MODE

WCPW

WCPW

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

SPACE AND BACKSPACE GROUP 1

SPACE

SPACE

BCE

REPEAT PATTERN F

BCE

BCE

SPACE

SPACE

SPACE

SPACE

TYPEIT

TYPEIT

TYPEIT

TYPEIT

DCW

BANDWIDTH & ALIGNMENT TEST

DCW

DCW

WCP

BANDWIDTH AND ALIGNMENT GROUP

WCP

WCP

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

SPACE AND BACKSPACE GROUP 1

SPACE

SPACE

WCPW

TYPE TEST PATTERN IN LOAD MODE

WCPW

WCPW

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

SPACE AND BACKSPACE GROUP 1

SPACE

SPACE

BCE

REPEAT PATTERN F

BCE

BCE

SPACE

SPACE

SPACE

SPACE

TYPEIT

TYPEIT

TYPEIT

TYPEIT

DCW

BANDWIDTH & ALIGNMENT TEST

DCW

DCW

WCP

BANDWIDTH AND ALIGNMENT GROUP

WCP

WCP

SPBSP1

SPACE AND BACKSPACE GROUP 1

SPBSP1

SPBSP1

SPACE

SPACE AND BACKSPACE GROUP 1

I/O PRINTER TEST

WT01 PAGE 20

PGLIN	LABEL	OPCOD	OPERAND	CT	ADDRES	INSTRUCTION
1226	TESTX	B	SPACE	7	02653	J 01333
1227		B	TYPEIT	7	02660	J 01289
1228		DCW	@SELECTED CHARACTER ROUTINE	40	02706	
1229						
1230		S	BUMPI	6	02708	S 00069
1231		B	TYPEIT	7	02714	J 01289
1232		DCW	@ENTER MODE-- M OR L@.G	18	02738	
1233		RCPW	MODE S	10	02740	L XTO 03419 R
1234		BEX1	*-16,M	7	02750	R 02740 M
1235		BAL	*@1	7	02757	R 02764 M
1236		B	TYPEIT	7	02764	J 01289
1237		DCW	@ENTER DATA FIELD@.G	16	02786	
1238	ENTERX	RCPW	PATRX	10	02788	L XTO 04352 R
1239						
1240		SBR	NEXT1 S	7	02798	G 00059 B
1241		BEX1	*-23,M	7	02805	R 02788 M
1242		BAL	*@1	7	02812	R 02819 M
1243		C	NEXT1,@PATRX	11	02819	C 00059 04442
1244		BE	TYPEX	7	02830	J 02914 S
1245		S	@1,NEXT1	11	02837	S 04443 00059
1246	CK4END	C	NEXT1,ENDOFX	11	02848	C 00059 00049
1247		BE	TYPEX	7	02859	J 02914 S
1248	EXPAND	MLCWS	PATRX@BUMPI,@NEXT1	12	02866	D 04LV2 00#MO 7
1249		SBR	NEXT1	7	02878	G 00059 B
1250		A	@1,BUMPI	11	02885	A 04443 00069
1251		A	@2,NEXT1	11	02896	A 04444 00059
1252		B	CK4END	7	02907	J 02848

I/O PRINTER TEST

WT01 PAGE 21

PGLIN	LABEL	OPCODE	OPERAND	CT	ADDRS	INSTRUCTION
1254	TYPEX	BCE	LMODE,MODE,L	12	02914	B 02957 03419 L
1255		B	WCP	7	02926	J 03100
1256		DCW	PATRNX	5	02937	04352
1257		B	WCP	7	02938	J 03100
1258		DCW	PATRNX	5	02949	04352
1259		B	*C25	7	02950	J 02981
1260						
1261	LMODE	B	WCPW	7	02957	J 03115
1262		DCW	PATRNX	5	02968	04352
1263		B	WCPW	7	02969	J 03115
1264		DCW	PATRNX	5	02980	04352
1265						
1266		BCE	TYPEX,IAD1,1	12	02981	B 02914 01001 1
1267	.					
1268	.					
1269	.					
1270	THEEND	B	TYPEIT	7	02993	J 01289
1271		DCW	3	48	03047	
1272		BNQ	CONTRL	7	03049	J 01007 Q
1273		BCE	TESTA,IAD3,1	12	03056	B 02007 01003 1
1274		B	LOADER	7	03068	J 00400
1275		H		1	03075	.
1276	.					
1277		ORG	*EX00			03100

*** END OF JOB ***2,G

ANY LAST REQUEST

REPEAT TEST-NO INITIALIZATION

ON TO NEXT PROGRAM

DEFINE PRECEDING BRANCH LENGTH

I/O PRINTER TEST

PGLIN	LABEL	OPCCD	OPERAND	TEST PATTERN TYPING ROUTINE	CT	ADDRS	INSTRUCTION
1279	*			TEST PATTERN TYPING ROUTINE			
1280							
1281	WCP	SBR	DATA	STORE ADDRESS OF DATA PATTERN	7	03100	G 00039 B
1282		B	SETOP	SET UP TYPE INSTRUCTION MODE	7	03107	J 03130
1283		DCW	2M2	MOVE MODE	1	03114	
1284							
1285	WCPW	SBR	DATA	STORE ADDRESS OF TEST PATTERN	7	03115	G 00039 B
1286		B	SETOP	SET MODE OF TYPE INSTRUCTION	7	03122	J 03130
1287		DCW	2L2		1	03129	
1288							
1289	SETOP	SBR	*E6	STORE M OR L OP CODE	7	03130	G 03142 B
1290		MLCWS	0, TYPETP	SET MODE IN TYPE INSTRUCTION	12	03137	D 00000 03198 7
1291		CW	6&DATA	SET ADDRESS	6	03149	D 000M6
1292		SAR	RETURN	FOR RETURN TO TEST ROUTINE	7	03155	G 00029 A
1293		S	TOTAL	ZERO TIMING COUNTER	6	03162	S 03595
1294		CS	BUFFER&82	CLEAR CUT OUTPUT ARFA	6	03168	/ 03582
1295		MLNA	4&DATA,*E6	SET ADDRESS OF TEST PATTERN	12	03174	D 000M4 03191 /
1296		MRCWG	0, BUFFER	SET TEST PATTERN INTO OUTPUT AREA	12	03186	D 00000 03500 L
1297	TYPETP	WCPW	BUFFER	TYPE TEST PATTERN	10	03198	L %TO 03500 W
1298	QVRLAP	NOPWM			1	03208	N
1299		BOLI	TIMER		7	03209	J 03230 1
1300		BCBI	TYPETP		7	03216	R 03198 2
1301		B	CK4ERR		7	03223	J 03248
1302	TIMER	A	TIME, TOTAL	ADD LOOP TIME TO TOTAL	11	03230	A 03587 03595
1303		BOLI	*-17	RETURN WHILE OVERLAP IN PROCESS	7	03241	J 03230 1
1304	CK4ERR	BAL	ERRORT	BRANCH TO ERROR ROUTINE	7	03248	R 03328 M
1305		BCE	EDITIT, IAD4, 1	EDIT TIME FOR TYPEOUT	12	03255	B 03274 01004 1
1306		B	CK4INQ	NO TIME TYPEOUT	7	03267	J 03314
1307	EDITIT	MLCWA	CTLFLD, RESULT&4	PREPARE RESULT FIELD	12	03274	D 03425 03430 X
1308		MCE	TOTAL-4, RESULT&4	EDIT TOTAL FOR TYPING	11	03286	E 03591 03430
1309		WCP	RESULT	TOTAL TIME FOR ONE LINE	10	03297	M %TO 03426 W
1310		BAL	*-16		7	03307	R 03297 M
1311	CK4INQ	BNQ	CONTRL	TO CONTROL ROUTINE	7	03314	J 01007 Q
1312		B	0&RETURN	RETURN TO TEST ROUTINE	7	03321	J 000+0

